TOSHIBA BIPOLAR DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

# TD62783AFN,TD62784AFN

### 8CH HIGH-VOLTAGE HIGH SOURCE-CURRENT DRIVER

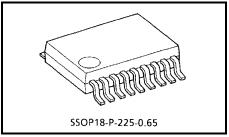
The TD62783AFN, TD62784AFN are comprised of eight source current Transistor Array.

These drivers are specifically designed for fluorescent display applications.

Applications include relay, hammer and lamp and display (LED) drivers.

### FEATURES

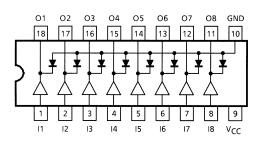
- Package Type : SSOP18 pin (0.65 mm pitch)
- High Ouptut Voltage : V<sub>CE</sub> (SUS) = 50 V (MIN)
- Output Current (Single Output) : IOUT = -500 mA (max)
- Output Clamp Diodes
- Single Supply Voltage
- Input Compatible with Various Types of Logic



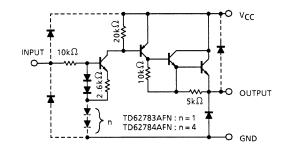
Weight: 0.09 g (typ.)

TYPE	DESIGNATION			
TD62783AFN	TTL, 5 V CMOS			
TD62784AFN	6~15 V PMOS, CMOS			

### **PIN CONNECTION (TOP VIEW)**



### SCHEMATICS (EACH DRIVER)



Note: The input and output parasitic diodes cannot be used as clamp diodes.

### ABSOLUTE MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT	
Supply Voltage	V <sub>CC</sub>	50	V	
Output Current	I <sub>OUT</sub>	-500	mA / ch	
Input Voltage	V <sub>IN</sub> (Note 1)	15	V	
input voltage	V <sub>IN</sub> (Note 2)	30	v	
Clamp Diode Reverse Voltage	V <sub>R</sub>	50	V	
Clamp Diode Forward Current	١ <sub>F</sub>	500	mA	
Power Dissipation	er Dissipation P <sub>D</sub> (Note 3)		W	
Operating Temperature	T <sub>opr</sub>	-40~85	°C	
Storage Temperature	T <sub>stg</sub>	-55~150	°C	

Note 1: TD62783AFN

Note 2: TD62784AFN

Note 3: On Glass Epoxy PCB (50 × 50 × 1.6 mm Cu 40%)

### **RECOMMENDED OPERATING CONDITIONS (Ta = -40~85°C)**

CHARACTERISTIC		SYMBOL	CONDITION		MIN	TYP.	MAX	UNIT	
Supply Voltage		V <sub>CC</sub>			—	_	50	V	
Output Current (			Iout	DC 1 Circuit		_	_	-350	
		(Note 3)		T <sub>pw</sub> = 25 ms, T <sub>j</sub> = 120°C Ta = 85°C, 8 Circuits	Duty = 10 %	_	-	-180	mA / ch
					Duty = 50 %	—	-	-38	
Input Voltage		(Note 1)	V <sub>IN</sub>			_	_	12	- V
		(Note 2)				_	_	24	
Input Voltage	Output ON	(Note 1)	V <sub>IN (ON)</sub>			2.0 5.0 1		15	
		(Note 2)			4.5 12.0 30		30	v	
	Output OFF	(Note 1)	V <sub>IN(OFF)</sub>			0	_	0.8	
		(Note 2)				0	_	2.0	
Clamp Diode Reverse Voltage		V <sub>R</sub>			_	_	50	V	
Clamp Diode Forward Current		١ <sub>F</sub>			_	_	400	mA	
Power Dissipation (Note 3)		PD			_	—	0.4	W	

Note 1: TD62783AFN

Note 2: TD62784AFN

Note 3: On Glass Epoxy PCB (50 × 50 × 1.6 mm Cu 40%)

### ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	TEST CIR- CUIT	TEST CONDITION	MIN	TYP.	MAX	UNIT
Output Leakage	Current	I <sub>CEX</sub>	$V_{CC} = V_{CC} MAX V_{DL} = 0.4 V$		100	μA		
Output Saturation Voltage			2	V <sub>IN</sub> = V <sub>IN (ON)</sub> , I <sub>OUT</sub> = -350 mA	_	_	2.0	V
		V <sub>CE (sat)</sub>		V <sub>IN</sub> = V <sub>IN (ON)</sub> , I <sub>OUT</sub> = -225 mA	_	_	1.9	
				V <sub>IN</sub> = V <sub>IN (ON)</sub> , I <sub>OUT</sub> = -100 mA	_	_	1.8	
Input Current	TD62783AFN	- I <sub>IN (ON)</sub>	3	V <sub>IN</sub> = 2.4 V	_	36	52	- μA
				V <sub>IN</sub> = 3.85 V	_	180	260	
	TD62784AFN			V <sub>IN</sub> = 5 V	_	92	130	
				V <sub>IN</sub> = 12 V	_	790	1130	
Input Voltage TD62783AFN TD62783AFN TD62783AFN TD62783AFN VIN (OFI TD62784AFN	TD62783AFN	VIN (ON)	- 4	V <sub>CE</sub> = 2.0 V	_	_	2.0	- V
	⊻IN (ON)			I <sub>OUT</sub> = −350 mA	_	_	4.5	
	TD62783AFN			I <sub>OUT</sub> = -500 μA	0.8	_	_	
	TD62784AFN	VIN (OFF)			2.0	_	_	
Supply Current		I <sub>CC</sub> (ON)	3	$V_{IN} = V_{IN (ON)}, V_{CC} = -50 V$	_	_	2.5	mA / ch
Clamp Diode Reverse Current		I <sub>R</sub>	5	V <sub>R</sub> = 50 V	_	_	50	μA
Clamp Diode Forward Voltage		V <sub>F</sub>	6	I <sub>F</sub> = 350 mA	_	_	2.0	V
Turn-On Delay		t <sub>ON</sub>	7	$V_{CC} = V_{CC}MAX, R_L = 125 \Omega$ $C_L = 15 pF$	_	0.15	—	μs
Turn-Off Delay		t <sub>OFF</sub>	1 '		_	3.0	_	

### **TEST CIRCIT**

1. ICEX

2. V<sub>CE (sat)</sub>

Vcc

VCE (sat)

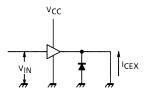
lout

3. I<sub>IN (ON)</sub>, ICC

Vcc

IN (ON)

VIN

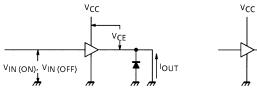


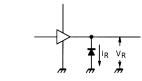
4. V<sub>IN (ON)</sub>, V<sub>IN (OFF)</sub>

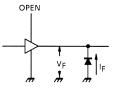


VIN

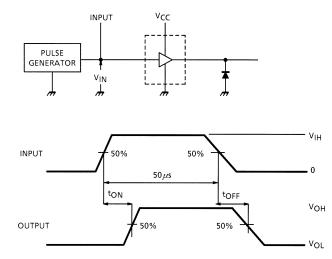








### $7. \quad t_{ON}, t_{OFF}$

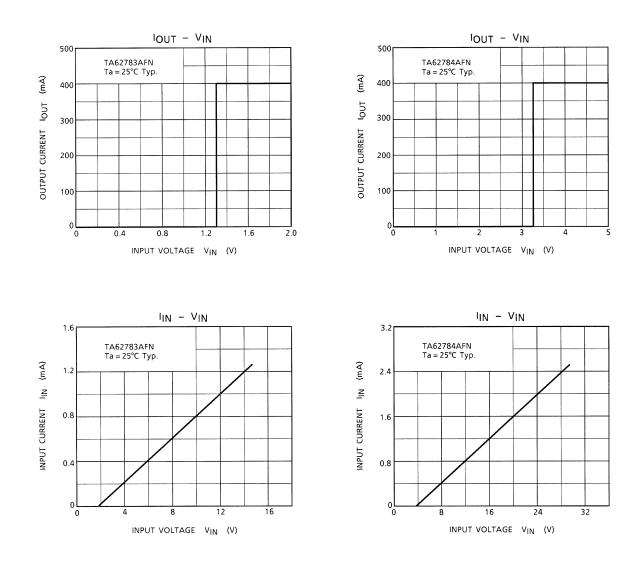


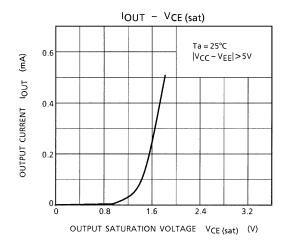
Note 1: Pulse Width 50  $\mu$ s, Duty Cycle 10% Ouptut Impedance 50  $\Omega$ , t<sub>r</sub> ≤ 5 ns, t<sub>f</sub> ≤ 10 ns Note 2: CL includes probe and jig capacitance.

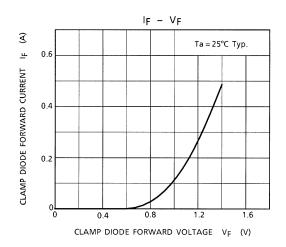
### **PRECAUTIONS for USING**

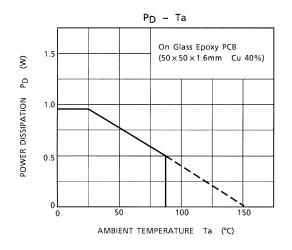
This IC does not integrate protection circuits such as overcurrent and overvoltage protectors. Thus, if excess current or voltage is applied to the IC, the IC may be damaged. Please design the IC so that excess current or voltage will not be applied to the IC.

Utmost care is necessary in the design of the output line, V<sub>CC</sub> and GND line since IC may be destroyed due to short-circuit between outputs, air contamination fault, or fault by improper grounding.





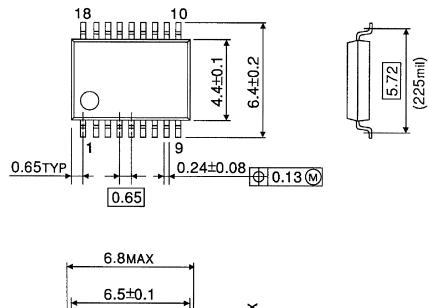


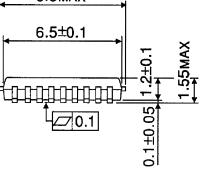


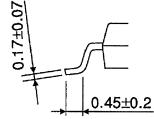
### PACKAGE DIMENSIONS

SSOP18-P-225-0.65

Unit: mm







Weight: 0.09 g (typ.)

### **Notes on Contents**

#### 1. Equivalent Circuits

The equivalent circuit diagrams may be simplified or some parts of them may be omitted for explanatory purposes.

#### 2. Test Circuits

Components in the test circuits are used only to obtain and confirm the device characteristics. These components and circuits are not guaranteed to prevent malfunction or failure from occurring in the application equipment.

### **IC Usage Considerations**

#### Notes on Handling of ICs

- The absolute maximum ratings of a semiconductor device are a set of ratings that must not be exceeded, even for a moment. Do not exceed any of these ratings. Exceeding the rating(s) may cause the device breakdown, damage or deterioration, and may result injury by explosion or combustion.
- (2) Use an appropriate power supply fuse to ensure that a large current does not continuously flow in case of over current and/or IC failure. The IC will fully break down when used under conditions that exceed its absolute maximum ratings, when the wiring is routed improperly or when an abnormal pulse noise occurs from the wiring or load, causing a large current to continuously flow and the breakdown can lead smoke or ignition. To minimize the effects of the flow of a large current in case of breakdown, appropriate settings, such as fuse capacity, fusing time and insertion circuit location, are required.
- (3) If your design includes an inductive load such as a motor coil, incorporate a protection circuit into the design to prevent device malfunction or breakdown caused by the current resulting from the inrush current at power ON or the negative current resulting from the back electromotive force at power OFF. IC breakdown may cause injury, smoke or ignition. Use a stable power supply with ICs with built-in protection functions. If the power supply is unstable, the protection function may not operate, causing IC breakdown. IC breakdown may cause injury, smoke or ignition.
- (4) Do not insert devices in the wrong orientation or incorrectly. Make sure that the positive and negative terminals of power supplies are connected properly. Otherwise, the current or power consumption may exceed the absolute maximum rating, and exceeding the rating(s) may cause the device breakdown, damage or deterioration, and may result injury by explosion or combustion. In addition, do not use any device that is applied the current with inserting in the wrong orientation or incorrectly even just one time.
- (5) Carefully select external components (such as inputs and negative feedback capacitors) and load components (such as speakers), for example, power amp and regulator. If there is a large amount of leakage current such as input or negative feedback condenser, the IC output DC voltage will increase. If this output voltage is connected to a speaker with low input withstand voltage, overcurrent or IC failure can cause smoke or ignition. (The over current can cause smoke or ignition from the IC itself.) In particular, please pay attention when using a Bridge Tied Load (BTL) connection type IC that inputs output DC voltage to a speaker directly.

### Points to Remember on Handling of ICs

#### (1) Heat Radiation Design

In using an IC with large current flow such as power amp, regulator or driver, please design the device so that heat is appropriately radiated, not to exceed the specified junction temperature (Tj) at any time and condition. These ICs generate heat even during normal use. An inadequate IC heat radiation design can lead to decrease in IC life, deterioration of IC characteristics or IC breakdown. In addition, please design the device taking into considerate the effect of IC heat radiation with peripheral components.

(2) Back-EMF

When a motor rotates in the reverse direction, stops or slows down abruptly, a current flow back to the motor's power supply due to the effect of back-EMF. If the current sink capability of the power supply is small, the device's motor power supply and output pins might be exposed to conditions beyond maximum ratings. To avoid this problem, take the effect of back-EMF into consideration in system design.

### **RESTRICTIONS ON PRODUCT USE**

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